



S/N 09/834751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al. Examiner: Craig Steven Miller
Serial No.: 09/834751 Group Art Unit: 2812
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Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC
TESTING

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

This responds to the Office Action mailed on October 28, 2003. Please amend the above-identified patent application as follows.

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